

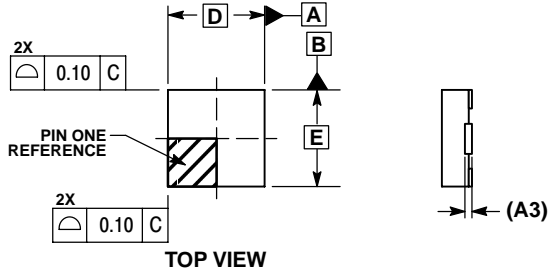


UDFN8, 1.6x1.6, 0.4P
CASE 517AC-01
ISSUE A

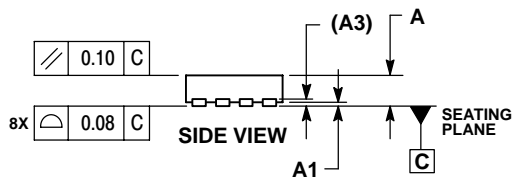
DATE 29 MAR 2006



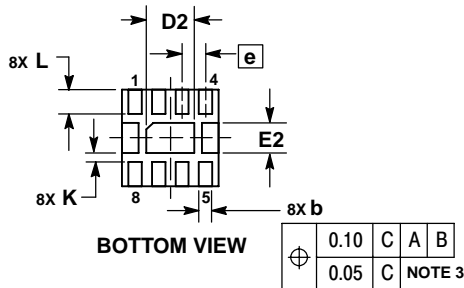
SCALE 4:1



TOP VIEW



SIDE VIEW



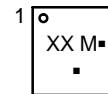
BOTTOM VIEW

NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.25 AND 0.30 mm FROM TERMINAL.
4. COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.
5. EXPOSED PADS CONNECTED TO DIE FLAG. USED AS TEST CONTACTS.

MILLIMETERS			
DIM	MIN	NOM	MAX
A	0.45	0.50	0.55
A1	0.00	0.03	0.05
A3	0.127 REF		
b	0.15	0.20	0.25
D	1.60 BSC		
D2	0.70	0.80	0.90
E	1.60 BSC		
E2	0.40	0.50	0.60
e	0.40 BSC		
K	0.20	---	---
L	0.20	0.30	0.40

GENERIC MARKING DIAGRAM*



X = Specific Device Code

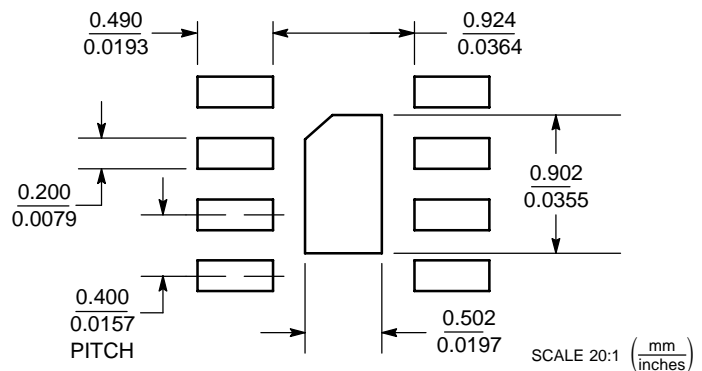
M = Date Code

▪ = Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "▪", may or may not be present.

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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STATUS:	ON SEMICONDUCTOR STANDARD	
NEW STANDARD:		
DESCRIPTION:	8 PIN UDFN, 1.6X1.6, 0.4P	PAGE 1 OF 2

